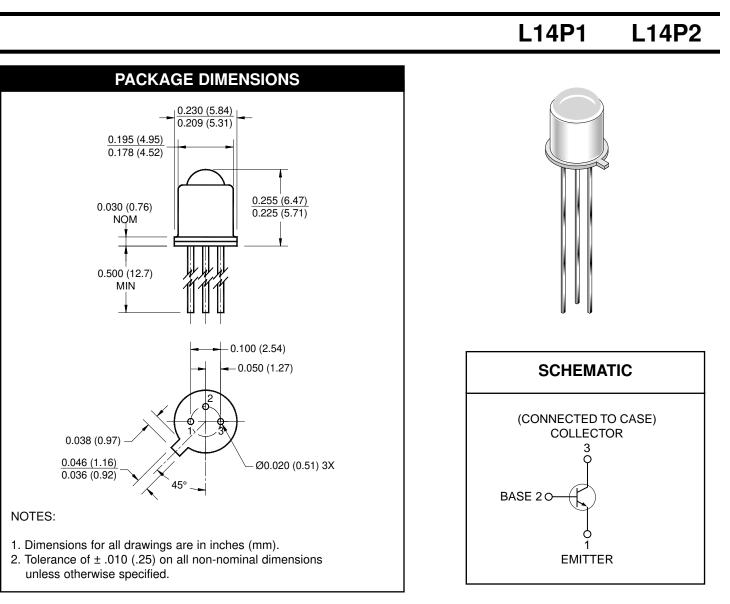


HERMETIC SILICON PHOTOTRANSISTOR



DESCRIPTION

The L14P1/L14P2 are silicon phototransistors mounted in a narrow angle, TO-18 package.

FEATURES

- Hermetically sealed package
- Narrow reception angle
- Devices can be used as a photodiode by wiring the collector and base leads.

FAIRCHILD

HERMETIC SILICON PHOTOTRANSISTOR

SEMICONDUCTOR®

L14P1 L14P2

ABSOLUTE MAXIMUM RATINGS (T _A = 25°C unless otherwise specified)								
Parameter	Symbol	Rating	Unit					
Operating Temperature	T _{OPR}	-65 to +125	°C					
Storage Temperature	T _{STG}	-65 to +150	°C					
Soldering Temperature (Iron) ^(3,4,5 and 6)	T _{SOL-I}	240 for 5 sec	°C					
Soldering Temperature (Flow) ^(3,4 and 6)	T _{SOL-F}	260 for 10 sec	°C					
Collector to Emitter Breakdown Voltage	V _{CEO}	30	V					
Collector to Base Breakdown Voltage	V _{CBO}	40	V					
Emitter to Base Breakdwon Voltage	V _{EBO}	5	V					
Power Dissipation $(T_A = 25^{\circ}C)^{(1)}$	PD	300	mW					
Power Dissipation (T _C = 25°C) ⁽²⁾	PD	600	mW					

NOTE:

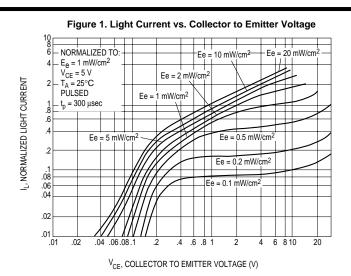
- 1. Derate power dissipation linearly 3.00 mW/°C above 25°C ambient.
- 2. Derate power dissipation linearly 6.00 mW/°C above 25°C case.
- 3. RMA flux is recommended.
- 4. Methanol or isopropyl alcohols are recommended as cleaning agents.
- 5. Soldering iron tip 1/16" (1.6mm) minimum from housing.
- 6. As long as leads are not under any stress or spring tension.
- 7. Light source is a GaAs LED emitting light at a peak wavelength of 940 nm.
- 8. Figure 1 and figure 2 use light source of tungsten lamp at 2870°K color temperature. A GaAs source of 3.0 mW/cm² is approximately equivalent to a tungsten source, at 2870°K, of 10 mW/cm².

ELECTRICAL / OPTICAL CHARACTERISTICS (TA =25°C) (All measurements made under pulse conditions)								
PARAMETER	TEST CONDITIONS	SYMBOL	MIN	ТҮР	MAX	UNITS		
Collector-Emitter Breakdown	I _C = 10 mA, Ee = 0	BV _{CEO}	30		—	V		
Emitter-Base Breakdown	I _E = 100 μA, Ee = 0	BV _{EBO}	5.0		—	V		
Collector-Base Breakdown	I _C = 100 μA, Ee = 0	BV _{CBO}	40		—	V		
Collector-Emitter Leakage	V _{CE} = 12 V, Ee = 0	I _{CEO}	—		100	nA		
Reception Angle at 1/2 Sensitivity		θ		±8		Degrees		
On-State Collector Current L14P1	$Ee = 0.5 \text{ mW/cm}^2$, $V_{CE} = 5 \text{ V}^{(7,8)}$	I _{C(ON)}	6.5		—	mA		
On-State Collector Current L14P2	$Ee = 0.5 \text{ mW/cm}^2$, $V_{CE} = 5 V^{(7,8)}$	I _{C(ON)}	13.0			mA		
On-State Photodiode Current	$Ee = 0.3 \text{ mW/cm}^2, \text{ V}_{CB} = 5 \text{ V}$	I _{CB(ON)}		6.0		μA		
Rise Time	$I_{\rm C}$ = 10 mA, $V_{\rm CC}$ = 5 V, $R_{\rm L}$ =100 Ω	t _r		10		μs		
Fall Time	$I_{\rm C}$ = 10 mA, $V_{\rm CC}$ = 5 V, $R_{\rm L}$ =100 Ω	t _f		12		μs		
Saturation Voltage L14P1	$I_{\rm C}$ = 0.8 mA, Ee = 0.6 mW/cm ^{2(7,8)}	V _{CE(SAT)}	_		0.40	V		
Saturation Voltage L14P2	$I_{\rm C}$ = 1.6 mA, Ee = 0.6 mW/cm ^{2(7,8)}	V _{CE(SAT)}	_		0.40	V		



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L14P1 L14P2



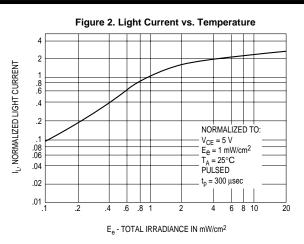
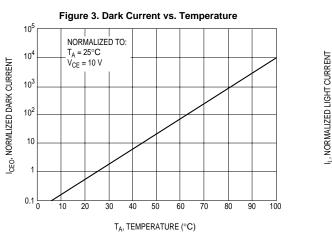


Figure 4. Light Current vs. Temperature



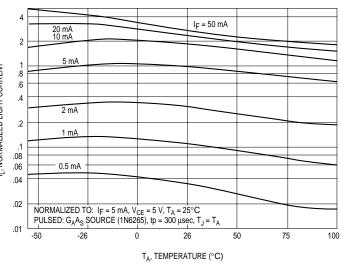
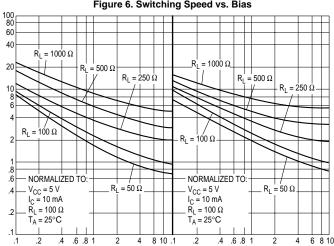


Figure 5. Angular and Spectral Response 110 100 .9 90 80 .8 **RELATIVE OUTPUT (%)** RELATIVE RESPONSE .7 60 .6 60 .5 50 40 .4 .3 30 20 .2 10 .1 40 500 600 700 800 900 1000 1100 20 -40 -20 0 θ, ANGULAR DISPLACEMENT λ, WAVE LENGTH FROM OPTICAL AXIS (NANOMETERS) (DEGREES)



I_{CE}, OUTPUT CURRENT (mA)

Figure 6. Switching Speed vs. Bias

RISE TIME

and tf, NORMALIZED SWITCHING LIGHT SPEED

FALL TIME



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L14P1 L14P2

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